IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| Patent Application Serial No | |
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| Filing Date | December 1, 2004 |
| Inventorship | Lay Har Angeline Tee et al |
| Assignee | SENSFAB PTE LTD |
| | |
| Examiner | Unknowr |
| Attorney's Docket No | DR10-006 |
| Title: Method of Forming Atomic Force | Microscope Tips |

INFORMATION DISCLOSURE STATEMENT References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the U.S. cited art are not included (1276 Off. Gaz. Pat. Off 55, 05 August 2003). No admission is made regarding whether all the submitted references are prior art.

This Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing of a first Office Action on the merits, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

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| U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | ATTY. DO DR10-006 | | SERIAL NO. 10/516,927 | | | |
| | | | | APPLICANT Lay Har Angeline Tee et al. | | | | | |
| | | | | FILING DATE December 1, 2004 | | | GROUP 1763 | | |
| | | | U.S. | PATENT DOCUMI | ENTS | | | | |
| Examiner Initial | | Document Number | Date | Name | · · · · · · · · · · · · · · · · · · · | Class | Subclass | belass Filing Date | |
| A | AA | 4,943,719 | 07-1990 | Akamine et al. | | | | | |
| | AB | 5,336,369 | 08-1994 | Kado et al. | | | | | |
| | AC | 5,614,663 | 03-1997 | Itoh et al. | | | | | |
| | AD | 5,965,218 | 10-1999 | Bothra et al. | | | | | |
| | AE | | | | , | | | | |
| | AF | | | | | | | | |
| | AG | | | | | | | | |
| | AH | | | | | | | | |
| | AI | | | | | | | | |
| | Al | | | | | | | | |
| | | | FOREIG | GN PATENT DOCU | IMENTS | | | , | |
| | | Document Number | Date | Country | | Class | Sub- class | Transla | ation No |
| | AK | JP2001-21478 | 01-200 | D1 Japan | | | | 168 | X |
| | AL | WO 01/06516 A1 | 01-200 | D1 PCT | | | | | |
| | AM | | | | | | | | |
| | | OTHER REFER | ENCES (in | cluding Author, Title | , Date, Pertin | ent Pages | , Etc.) | | |
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.